

Abstract of the Disclosure:

A semiconductor module with a plurality of interface circuits has a configuration for the self-test of interface circuits, with two equally sized groups of interface circuits such that each interface circuit of the first group is assigned exactly one interface circuit of the second group. A circuit interacts with the first group and serves for generating test signals which can be output via the interface circuits of the first group. Another circuit interacts with the second group and serves for receiving and processing test signals received via the interface circuits of the second group, so that a connection of the assigned interface circuits of the first and second groups enables a self-test, the first and second groups of interface circuits having a separate voltage supply. This enables good test coverage by separate variation of the voltage of transmitting and receiving group.

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